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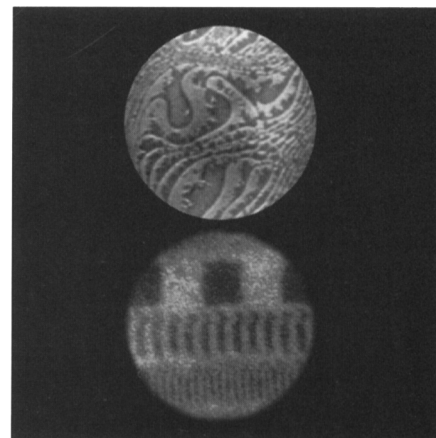
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ON THE COVER: Top: *In situ* determination of exact monolayer coverage for Co on W(110) at 650 K. Bottom: Magnetic microscopy using x-ray magnetic circular dichroism. The image is of magnetic domains on a CoPtCr magnetic-recording disk produced by subtracting images taken at the L_3 and L_2 edges of Co using circularly polarized x-rays. The bit pattern rows are 10 μm tall and decrease in width from 10 μm in the upper row through 2 μm to 1 μm in the lower row. The magnetization direction of the domains lies along the rows. For more information, see "SPLEEM of Magnetic Surfaces and Layered Structures" by Poppa et al. on page 38 and "X-Ray Magnetic Circular Dichroism Spectroscopy and Microscopy" by Smith and Padmore on page 41.

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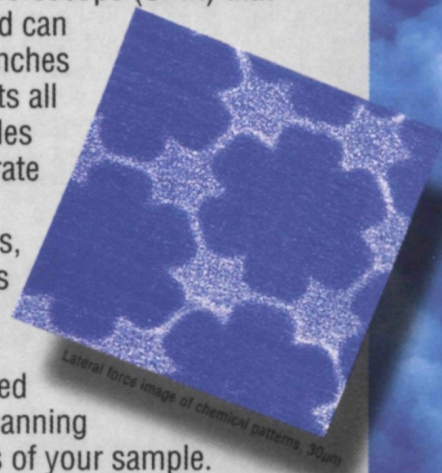
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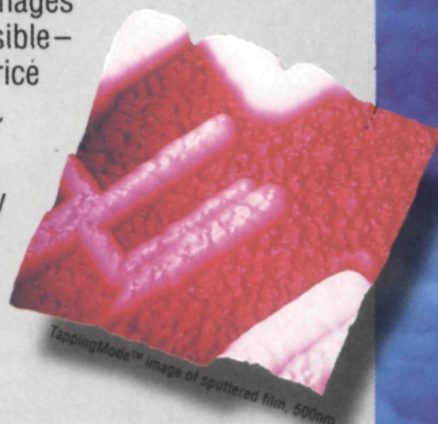
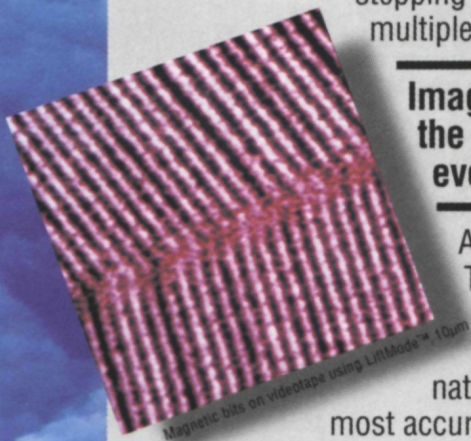
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